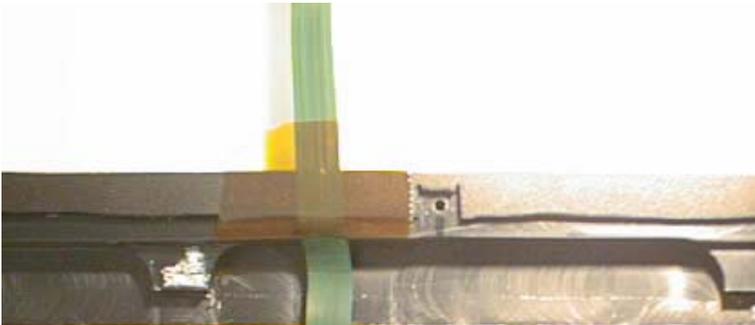
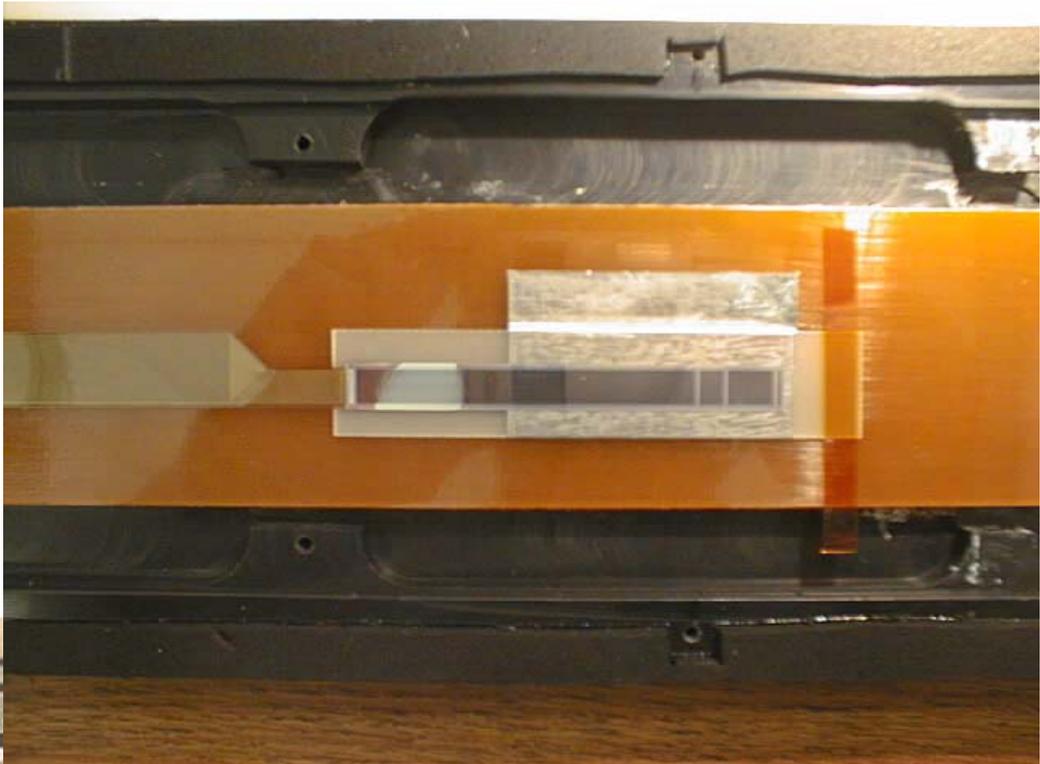
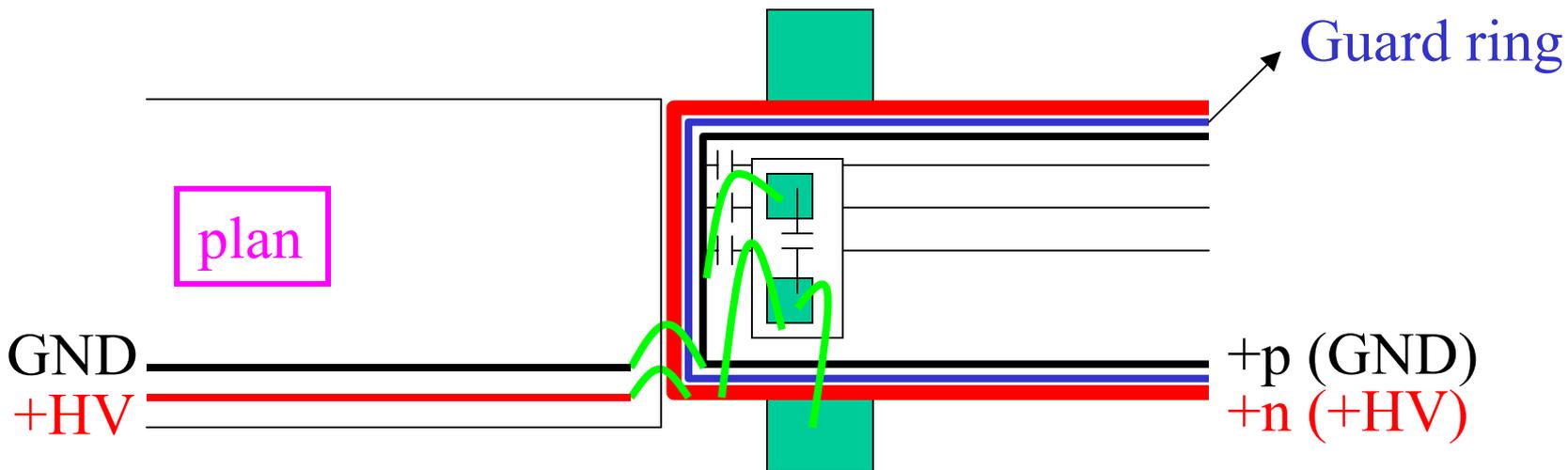
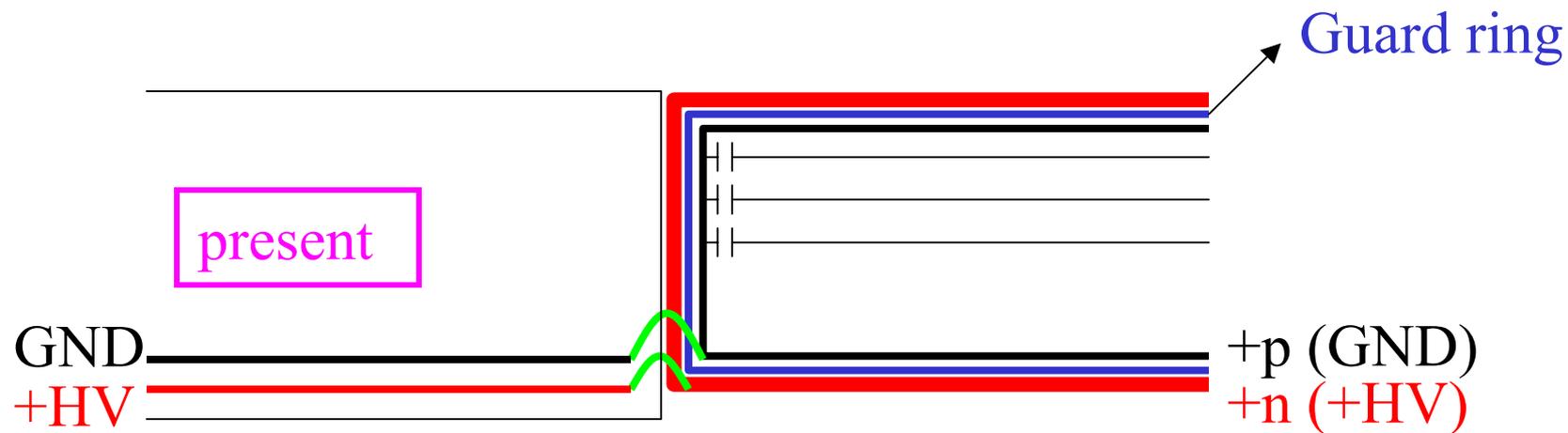
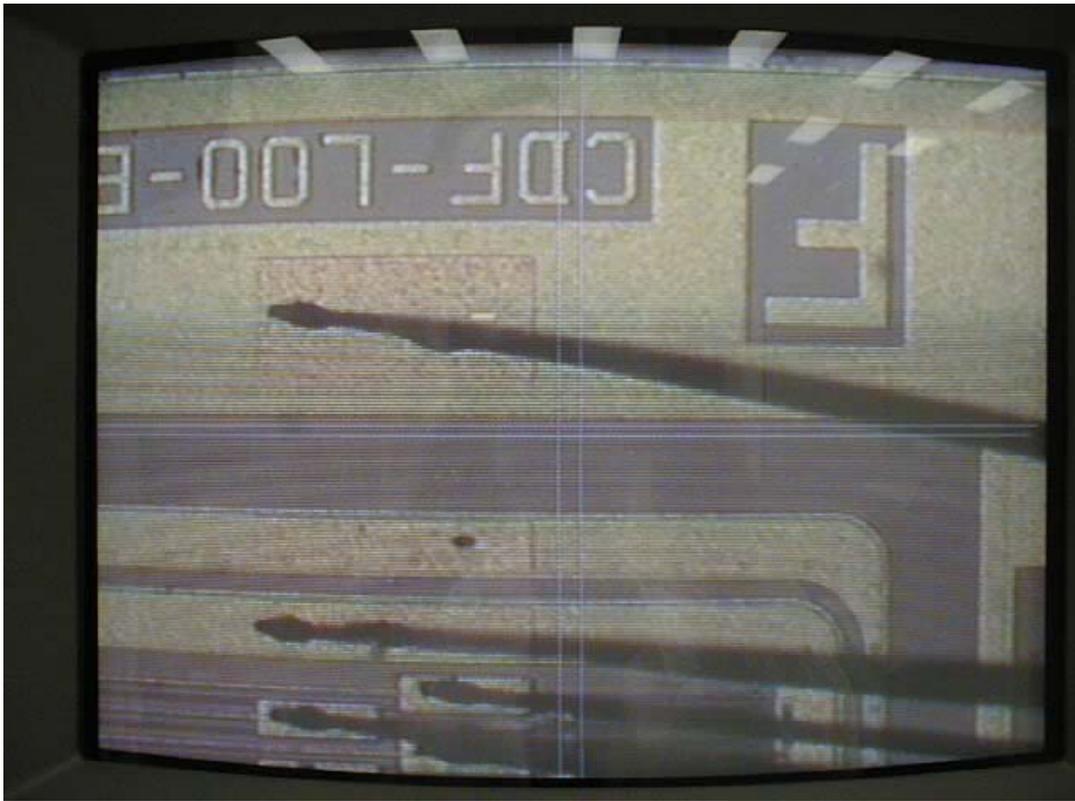


## Status of Layer 0 Prototype

- The assembly in the dark box.
- Read-out is OK. → pedestal measurement using the burn-in test stand for run 2A.
- Cannot apply the bias voltage above  $\sim 5V$ .  
← problems with the sensor???
- Another prototype. ← may need another analog cable!
- Noise study without depletion. (higher noise)

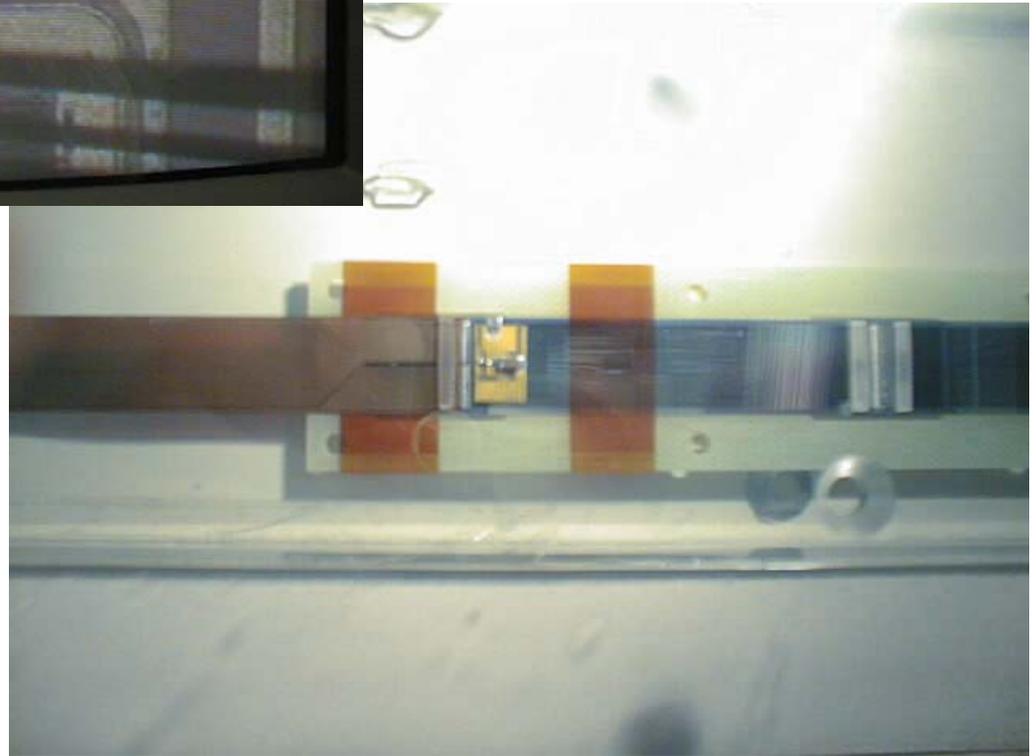




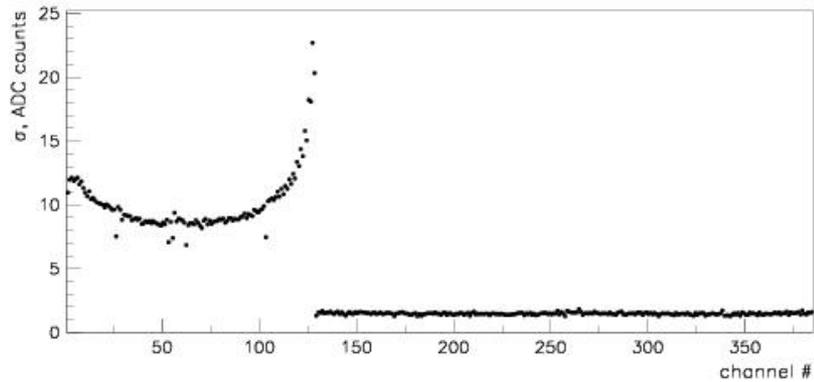
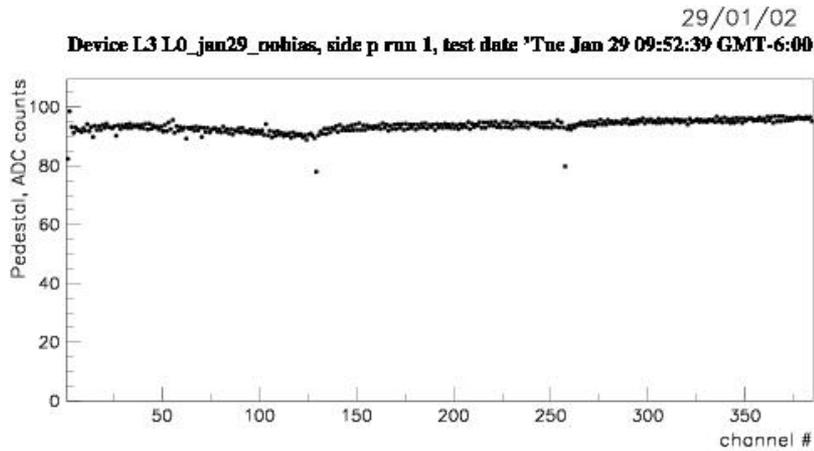


bonding of our  
prototype

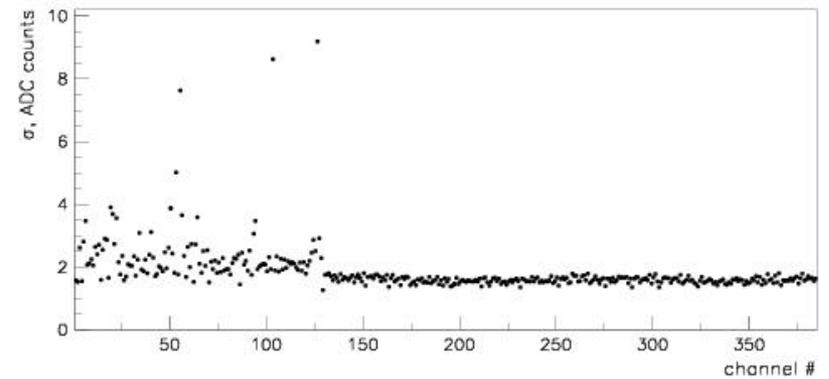
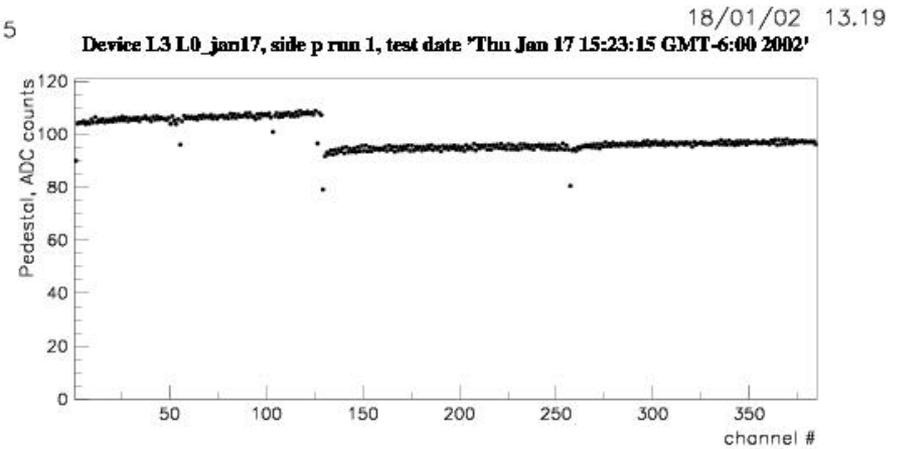
CDF Layer 0 for run 2A



# Total noise (=raw $\sigma$ of pedestal) without bias

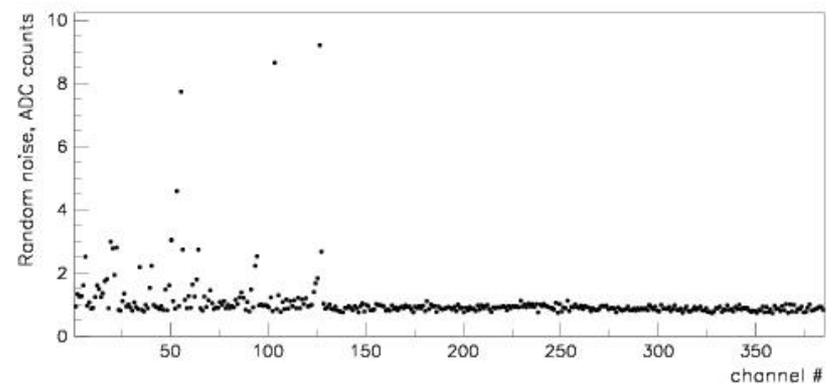
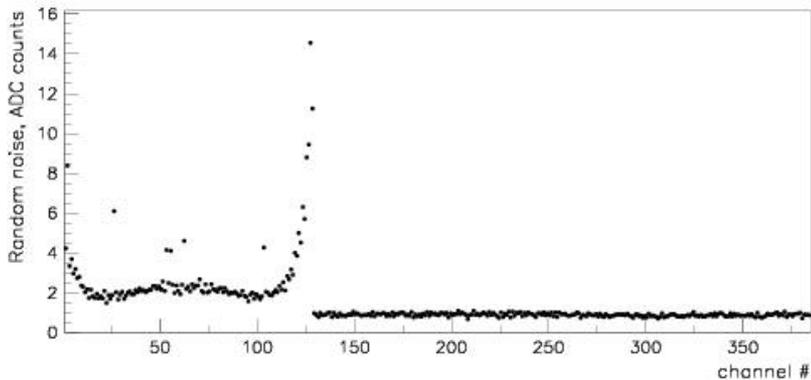
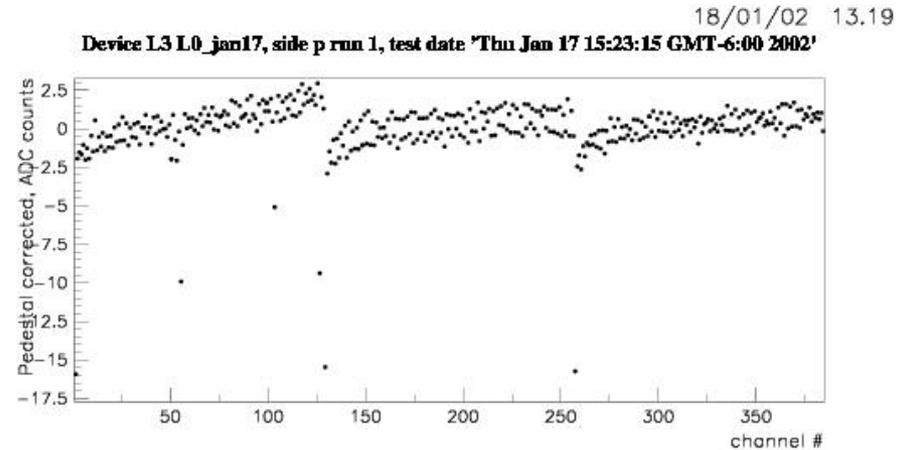
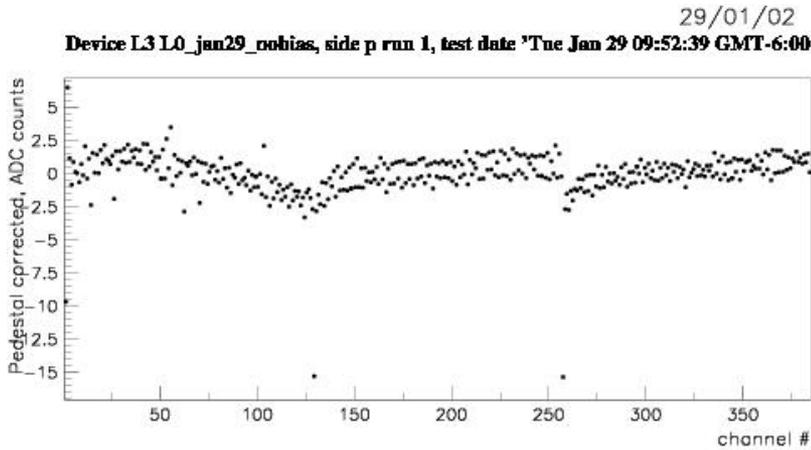


Inside the dark box



No dark box

# Random noise (common mode noise subtracted) without bias



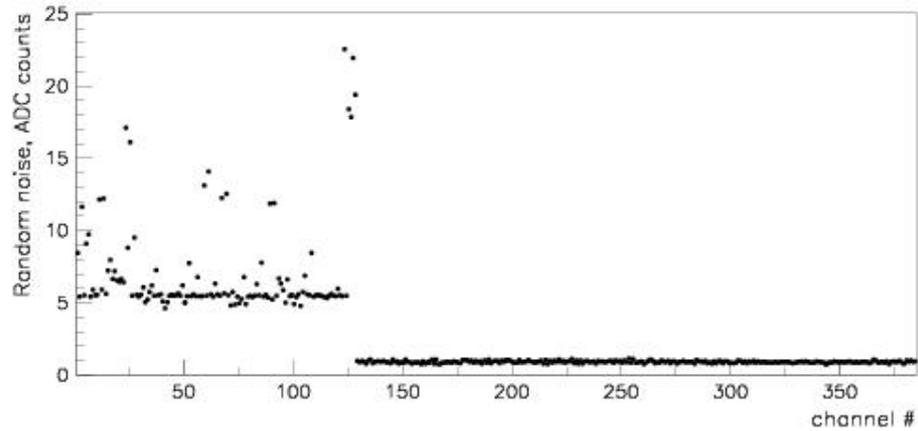
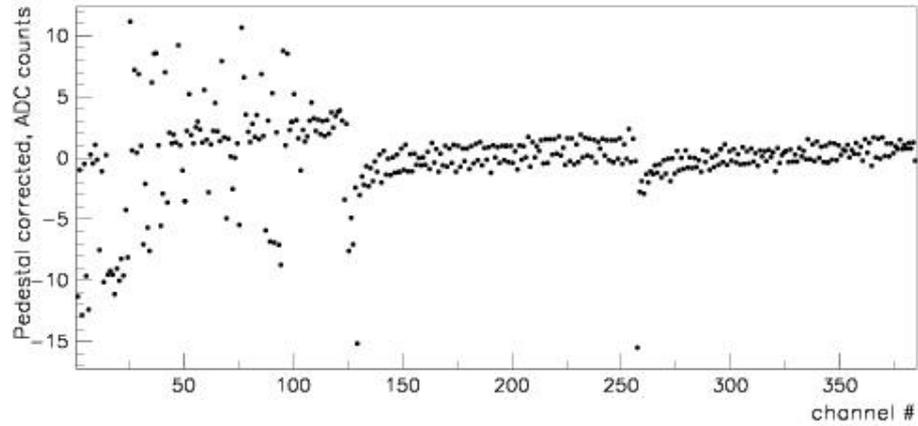
Inside the dark box

No dark box

# Random noise @ 5V bias

24/01/02 10.24

Device L3 L0\_jan24\_7v, side p run 1, test date 'Thu Jan 24 10:23:24 GMT-6:00 200



Capacitance of analog cable with the spacer candidate (polypropylene mesh & urethane foam)

spacer	(1) Meas (pF/cm)	(1) Calc (pF/cm)	(2) Meas (pF/cm)	(3) Calc (pF/cm)
none	0.355	0.322	0.390	0.358
Attached to bottom	0.355	0.328	0.376	N/A
Attached to top	0.362 0.362	0.372	0.398	N/A

1. Only the probe region is put on the glass substrate.
2. Whole cable put on the glass substrate.

Dielectric constants of 1.5 for the polypropylene and 5.0 for the glass are used in the calculation.